

UK Advanced Instrumentation Training

Circuit Design 3 & 4 Simulation LTspice 1 & 2

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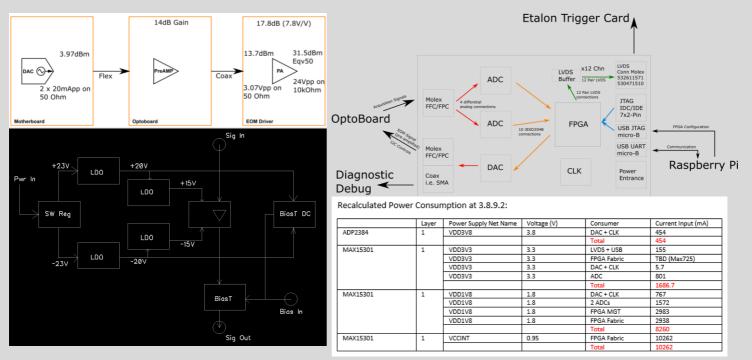
Workflow

Simulation

- Analyze -> Block Diagram, Specs
- Schematic -> Circuit topology, Constraints
- Layout -> GERBER, BOM, Assembly-files
- Manufacturing (fabrication, population, assembly)
- Debug, Characterization -> Reports
- (Revision)

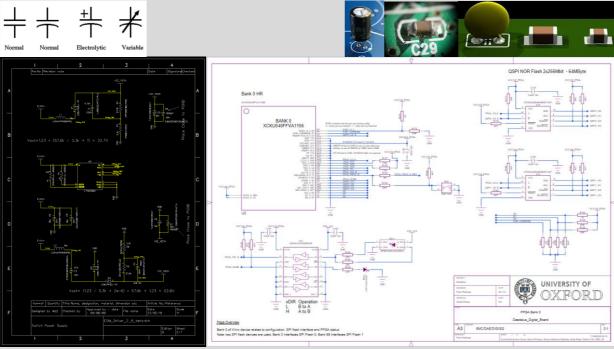


- Workflow
 - Analyze -> Block Diagram, Specs



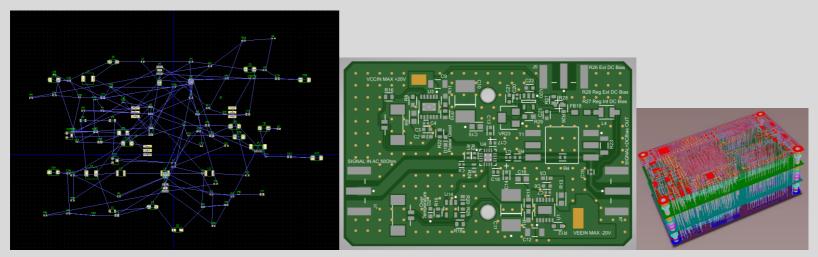


- Workflow
 - Schematic -> Circuit topology, Constraints





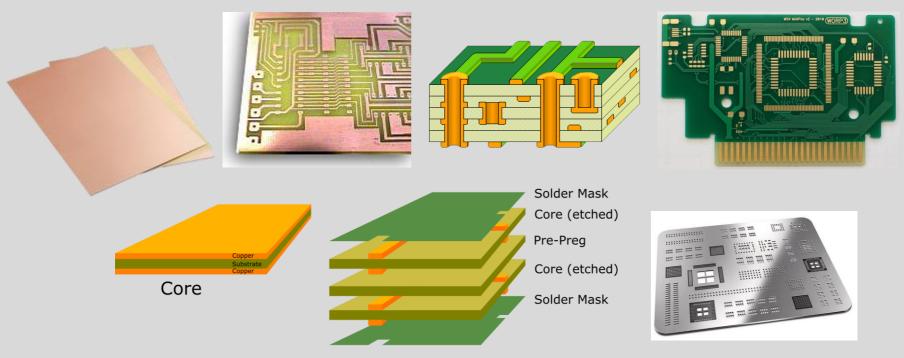
- Workflow
 - Layout -> GERBER, BOM, Assembly-files



Source: https://www.wellpcb.com/

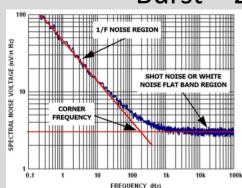


- Workflow
 - Manufacturing (fabrication, population, assembly)

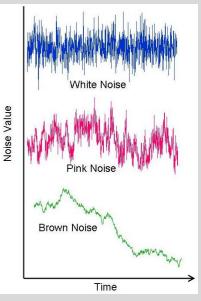




- Noise
 - Thermal ~ quasi-white, Gaussian, 4kTR; Conductor
 - Shot ~ white, Gaussian, 2*e*|*I*|; Semiconductor
 - 1/*f*, flicker ~ *f*-depend; Anything



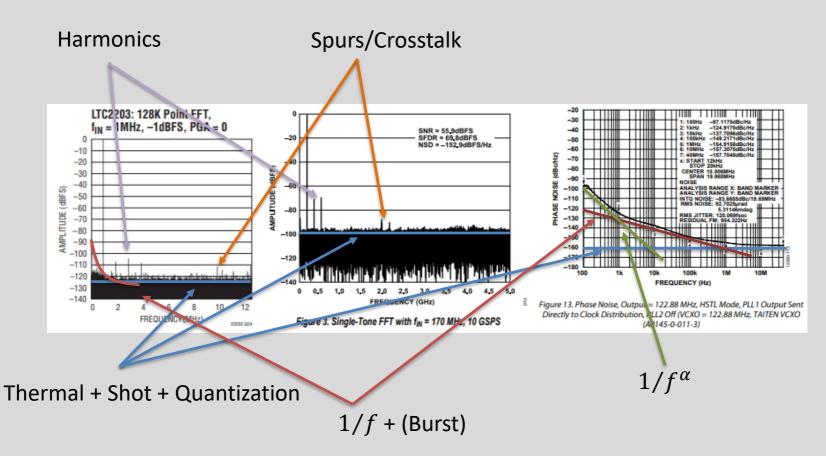
• Burst ~ 2-value, *f*-depend; Semiconductor





- Interference/Crosstalk
 - Data/Clock dependent ~ non-stationary, *f*-depend
- Systematic
 - Harmonics, Spurs ~ *f*-depend; Amp-linearity, ADC, DAC
 - Quantization Noise ~ quasi-white, uniform; ADC
 - Aliasing/Mirror Noise~ Signal x Sinc, uniform; ADC, DAC
 - Clock Phase Noise ~ $1/f^{\alpha}$; resonant, quartz, PLL







• Noise

• Units PSD vs PSD

$$\overline{P} = \lim_{T \to \infty} \frac{1}{T} \int_{-T/2}^{T/2} \frac{x^2(t)}{R} dt$$

 $\bar{P} = \int_0^B S_x(f) \mathrm{d}f$

x is the random variable of noise, with the unit of voltage Resistivity R is sometimes ignored to 1, \overline{P} is average power

B is the bandwidth, S_{χ} is the power spectrum density, with the unit of Power per Bandwidth, i.e. dBm/Hz

 $x_{\rm RMS} = \sqrt{\bar{P}R}$

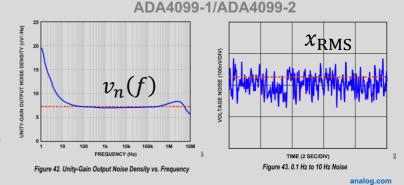
 $x_{\rm RMS}$ is the root-mean-square of the noise, with the unit of voltage

$$v_n(f) = \sqrt{\overline{S_x(f)}R} = \sqrt{\frac{2}{R}}$$

² This is only in white noise, $v_n(f)$ is the voltage \overline{B} spectrum density, with the unit of V/ $\sqrt{\text{Hz}}$



- Noise
 - Conversion
 - OdBm = 0.632V_{PP} = 0.233 V_{RMS}
 - Quantify and Comparison



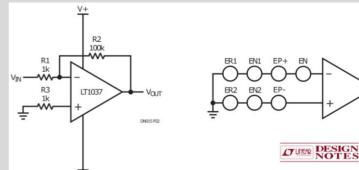
- *v_n* as a number gives floor
- x_{RMS} at low frequency tells flicker

$x_{\rm RMS} = \sqrt{PR}$	
$v_n(f) = \sqrt{\overline{S_x(f)}R} = \sqrt{\frac{1}{2}}$	$\frac{\bar{x}^2}{RB}$

VOISE PERFORMANCE				
Input Voltage Noise	f = 0.1 Hz to 10 Hz	150	150	nV p-p
	1/f noise corner	6	6	Hz
	f = 100 Hz	7	7	nV/\H
Over-The-Top	f = 100 Hz, V _{CM} > +V _S	8	8	nV/√H
Input Current Noise	f = 100 Hz	0.5	0.5	pA/\H
Over-The-Top	f = 100 Hz, V _{CM} > +V _S	5	5	pA/\H



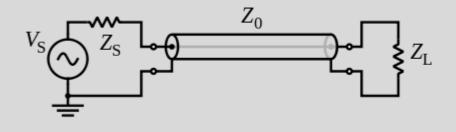
- Noise
 - Paths
 - Signal Input



- Resistive Components
- Semiconductor Devices
- Non-Linear (not LTI)
- Power Supplies
- Indirect Coupling

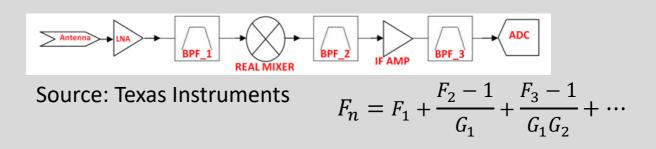


- Noise
 - Paths
 - Signal Input



- Antenna, transducer -> matching network
- Previous Stage of Amps

-> termination





f(Hz)

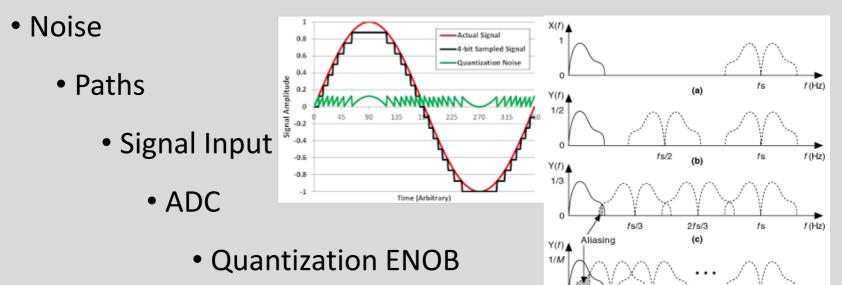
fs

fs/M

2fs/M

(d)

Circuit Design, Noise, Grounding

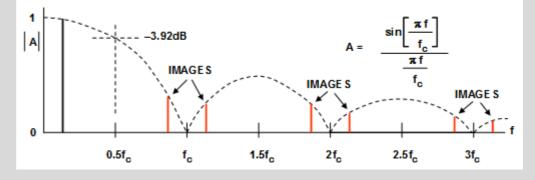


• Aliasing

$$x[n] = \sum_{n} \int s(t)\delta(t - nT_{\rm S})dt$$

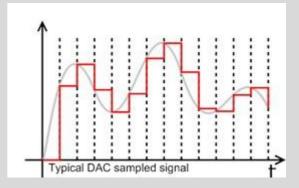


- Noise
 - Paths
 - Signal Input



- DAC
 - Quantization ENOB
 - Mirror/Image

$$s(t) = \sum_{n} x[n] * \operatorname{rect}\left(\frac{t}{T_{\rm S}}\right)$$





DN015 F03

DESIGN NOTES

Circuit Design, Noise, Grounding

R2 100k

LT1037

Van

DN015 F02

1k

R3 1k

- Noise
 - Paths
 - Resistive Components
 - Semiconductor Devices

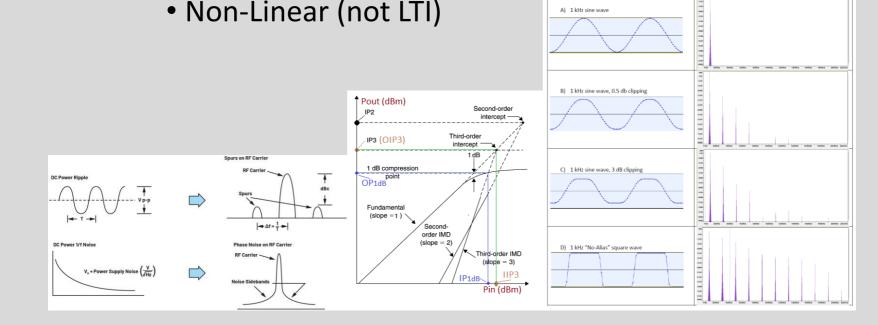


FFT

Waveform

A) 1 kHz sine wave

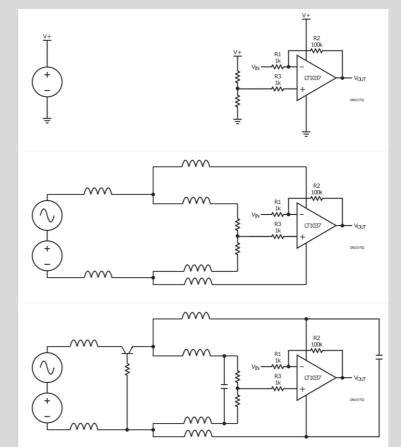
- Noise
 - Paths
 - Non-Linear (not LTI)





- Noise
 - Paths
 - Power Supplies
 - Indirect Coupling

• Power integrity





10

100

nF X7F

1 nF, NPC

1000

Ζ(Ω)

1000

100

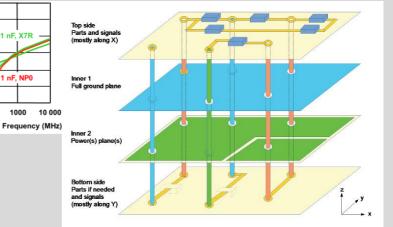
10 100 nF X7R 1

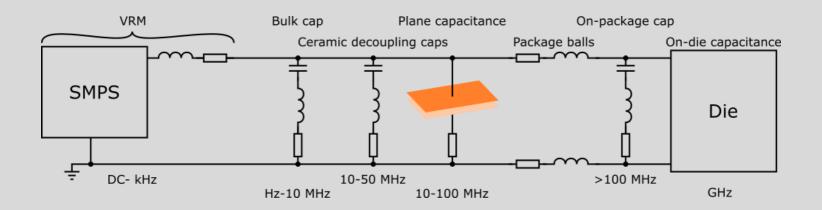
0.1

0,01

1

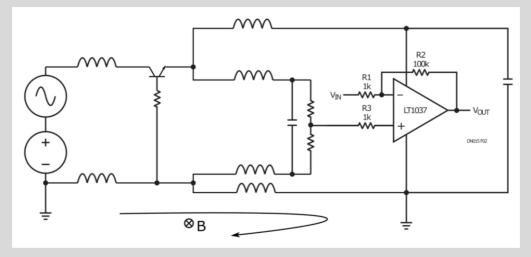
- Noise
 - Paths
 - Power Supplies
 - Indirect Coupling





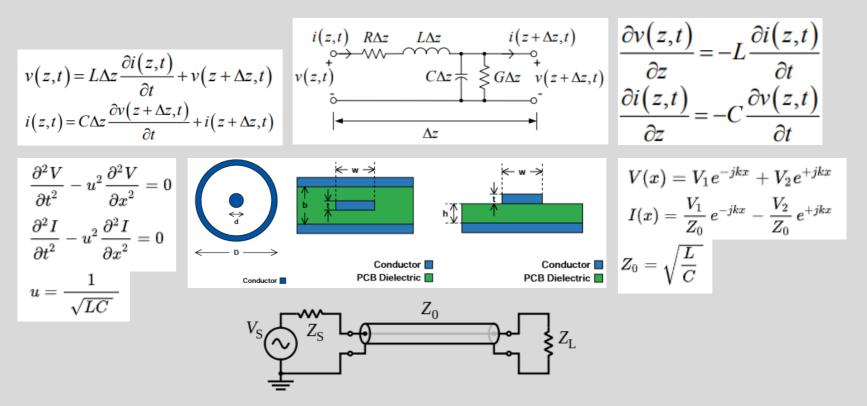


• Grounding





• Transmission Line Theory





- Signal Integrity
 - Designing and Maintaining Trace Structure
 - Termination

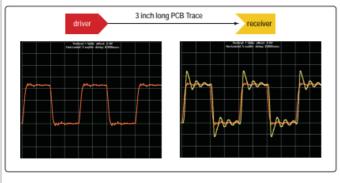
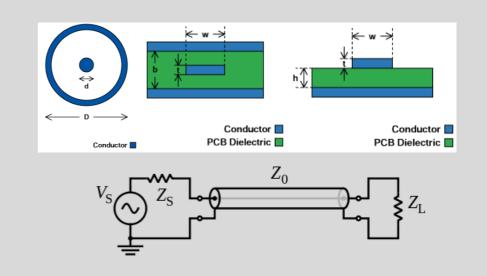


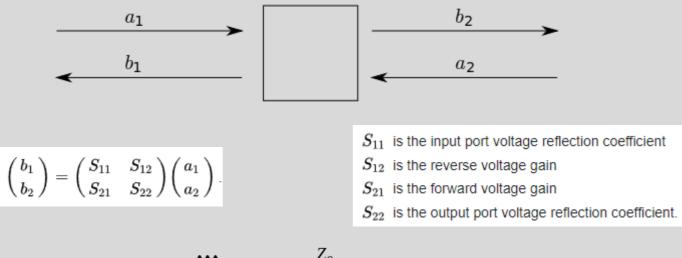
Figure 1. A signal as it emerges from the driver chip (left) is distorted by multiple reflections from impedance discontinuities at both ends (right).

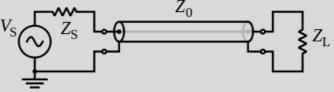
Source: Keysight





• Scattering Parameter (S-Parameter)







• Scattering Parameter (S-Parameter)

	ta, Drawings & Downloads DATASHEET					HMC1	049LP5E	GaAs pHENT MMIC Low Nose Arapite, 0.3 - 20 CHz
I	View Data					Overview Eval	astion Kits Documentation	1 Tools & Simulators Ruference Materials Design Resources
	View Graphs							
Ceramic, hermetically scalad *********************************	<pre>space shadow LEAS -Circuits Laboratory: 11/3/2015 at 1:45:15 ACTA File Format : MMIC Amplifier I: CMA-81+ Unit 1 une: T8-829-81+ NO POR OUT: PORT 1 - PIN 2, P CONDITIONS: Temp= + 85 R/LOT#: n/a DATE CODE: ork Analyze: PNA-X NS</pre>	T EXTENSION. ORT 2 - PIN 7, GROUND (Deg C) RF Power= -25 1448 242A S/N 71404 CAL DUE	.00 (dBm) V limit=5 : 12/5/2015			Data Sheet S-Paramete		<pre>1 #Agilent Technologics,f6361A,US43140893,A.06.04.32 2 !Agilent Technologics,f6361A,US43140893,A.06.04.32 3 !Date: Wednesday, November 18, 2012 13:50:33 1 (Correction: Sil/Full 2 Port(1,2)) S2l(Full 2 Port(1,2)) S12(Full 2 Port(1,2)) S22(Full 2 Port(5 !S2P File: Measurements: S11, S21, S12, S22: 6 # GHz 5 dB R 50 7 .0.01 -2.404 -11.185 19.791 170.825 -39.68 70.612 -12.811 177.269 </pre>
13 !	pply/Multimeter: HP E3	632A S/N 63249 CAL DUE	: 12/11/2015					8 0.10998 -9.163 -64.832 17.03 156.889 -28.235 13.797 -7.916 172.448
	000 -38.1764500 000 -42.6544600 000 -39.2277800 000 -43.5005400 000 -45.7234300 000 -42.7495200	S11 Deg S21 dB -166.7859000 10.564 - <th>700 179.9357000 400 178.6488000 500 178.0562000 900 177.9172000 800 177.2186000 900 177.2186000 900 176.8549000 900 176.5308000</th> <th>-20.4535600 -20.4699600 -20.5039200 -20.4823700 -20.5057600 -20.4884000 -20.4867100 -20.4854800 -20.4854800 -20.4854800</th> <th>S12 Deg -0.4232590 0.2922911 -0.9079536 -1.2963140 -1.3303600 -1.6336710 -1.8795270 -2.0976540 -2.6154540 -2.8611950</th> <th>S22 d8 -20.3147700 -19.5530300 -20.3498200 -20.7143700 -20.4270900 -20.452700 -20.4572700 -20.4672700 -20.5594500 -20.5885600 -20.5889600</th> <th>-5.7504110 -0.6635373 0.4261140 -1.7378030 -2.6354570 -2.9222600 -3.3060280 -3.8508110 -5.0186350</th> <th>16 0.90982 -19.671 -174.056 16.298 65.561 -26.856 -101.933 -7.501 63.655 17 1.00988 -19.878 169.391 16.314 53.504 -26.791 -114.001 -7.489 51.038 1.10978 -20.069 153.053 16.356 41.451 -26.714 -126.662 -7.486 36.615</th>	700 179.9357000 400 178.6488000 500 178.0562000 900 177.9172000 800 177.2186000 900 177.2186000 900 176.8549000 900 176.5308000	-20.4535600 -20.4699600 -20.5039200 -20.4823700 -20.5057600 -20.4884000 -20.4867100 -20.4854800 -20.4854800 -20.4854800	S12 Deg -0.4232590 0.2922911 -0.9079536 -1.2963140 -1.3303600 -1.6336710 -1.8795270 -2.0976540 -2.6154540 -2.8611950	S22 d8 -20.3147700 -19.5530300 -20.3498200 -20.7143700 -20.4270900 -20.452700 -20.4572700 -20.4672700 -20.5594500 -20.5885600 -20.5889600	-5.7504110 -0.6635373 0.4261140 -1.7378030 -2.6354570 -2.9222600 -3.3060280 -3.8508110 -5.0186350	16 0.90982 -19.671 -174.056 16.298 65.561 -26.856 -101.933 -7.501 63.655 17 1.00988 -19.878 169.391 16.314 53.504 -26.791 -114.001 -7.489 51.038 1.10978 -20.069 153.053 16.356 41.451 -26.714 -126.662 -7.486 36.615



Matching Network

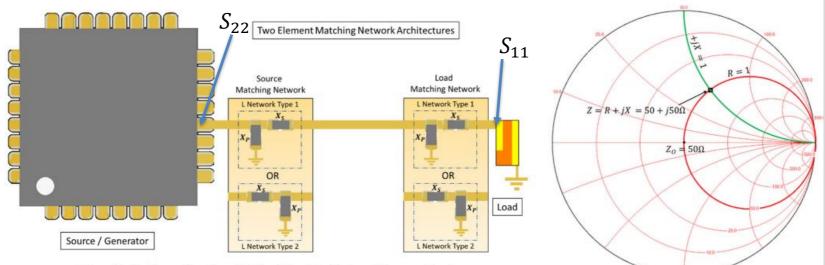
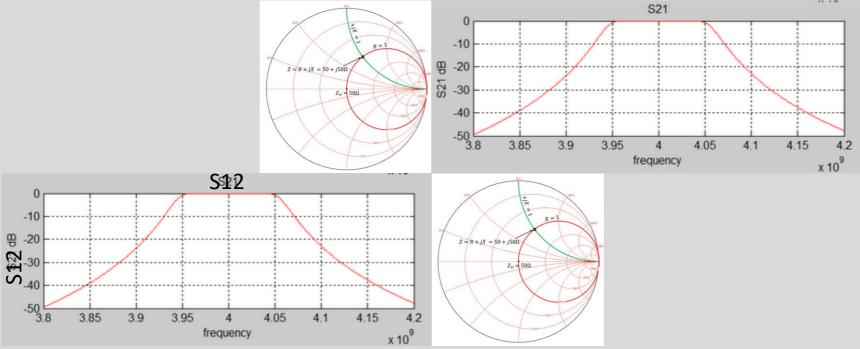


Figure 4.1. Two Element Impedance Matching Network Architecture at Source and Load

Source: SiLabs

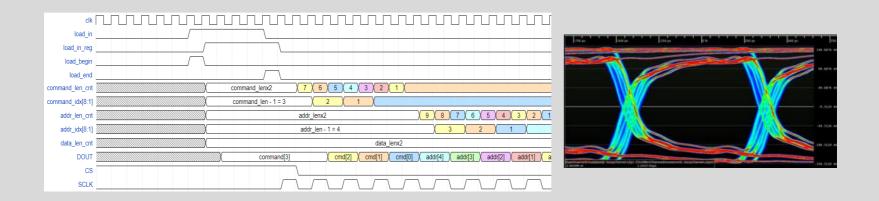


• Simulation of Amplifier Design



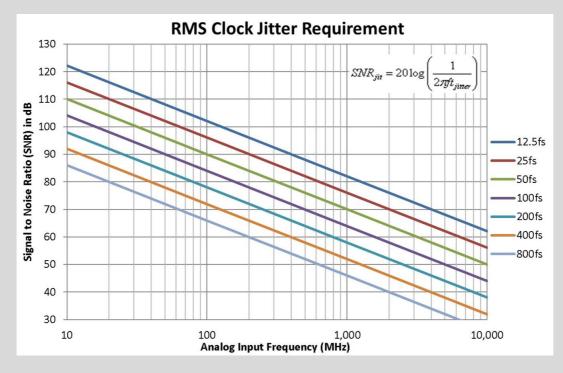


• Clock Jitter/Phase noise in Digital System/Comms



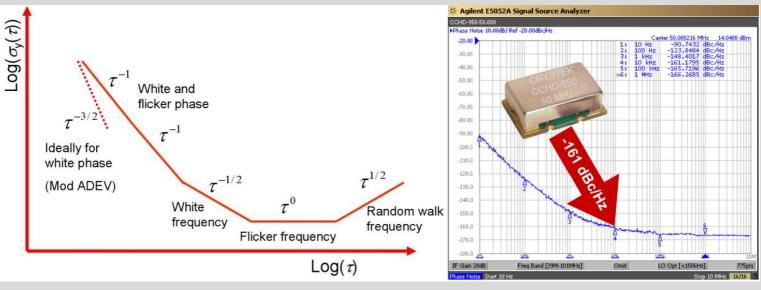


• Clock Jitter/Phase noise in DAQ





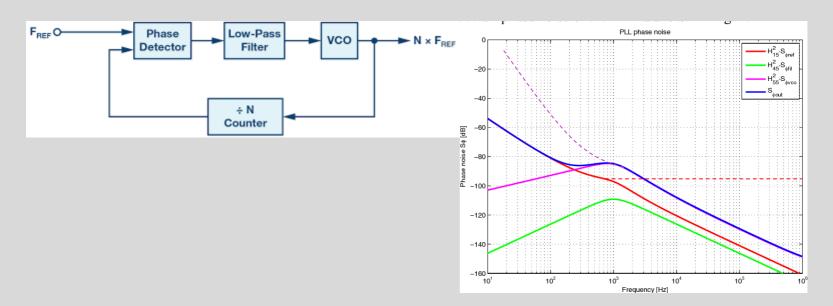
Clock Jitter/Phase noise



Source: NIST



• Phase Locked Loop





S21

\$11

Circuit Design, Amplifier, Clock

HMC1049LP5E

Continuous PDESS (T = 85°C)

Storage Temperature

ESD Sensitivity (HBM)

affect product reliability

Operating Temperature

Paddle)

Temperature

(Derate 37.1 mW/°C Above 85°C)

Thermal Resistance (Channel to Ground

Stresses at or above those listed under Absolute Maximum

Ratings may cause permanent damage to the product. This is a

stress rating only; functional operation of the product at these

Ratino

7 V

18 dBm

175°C

3.34W

26 0 0 0

Class 1A

-65°C to +150°C

-40°C to +85°C

-2V to +0.2V

ABSOLUTE MAXIMUM RATINGS Table 2 Parameter How to read datasheet Drain Bias Voltage (Vm Drain Bias Voltage (RF Out/Vpp) **RF Input Power** Gate Bias Voltage Vor Channel Temperature



GENERAL DESCRIPTION

The HMC1049LP5E is a GaAs MMIC low noise amplifier (LNA) that operates between 0.3 GHz and 20 GHz. This LNA provides 15 dB of small signal gain, 1.8 dB noise figure, and an IP3 output of 29 dBm, yet requires only 70 mA from a 7 V supply. The P1dB output power of 14.5 dBm enables the LNA to function as a local oscillator (LO) driver for balanced, I/Q, or

SPECIFICATIONS

 $T_A = 25^{\circ}C$, $V_{DD} = 7$ V, $I_{DD} = 70$ mA³

Parameter	Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	Unit
FREQUENCY RANGE	0.3		1	1		14	14		20	GHz
GAIN	13.5	16.5		12	15		10	13		dB
Gain Variation Over Temperature		0.006			0.019			0.017		dB/°C
NOISE FIGURE		2.5	3.5		1.8	2.5		2.7	4.0	dB
RETURN LOSS										
Input		15			13			14		dB
Output		8			15			13		dB
OUTPUT										
Output Power for 1 dB Compression (P1dB)		15			14.5			13		dBm
Saturated (P _{SAT})		18			17.5			16		dBm
Output Third-Order Intercept (IP3) ²		31			29			26		dBm
TOTAL SUPPLY CURRENT		70			70			70		mA

² Measurement taken at Pour/tone - 8 dBm



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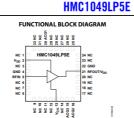
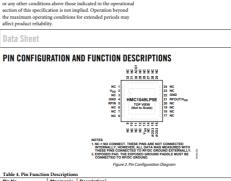


image rejection mixers. $V_{\mbox{\tiny DD}}$ can also be applied to Pin 21, although Pin 21 requires a bias tee with VDD = 4 V. The HMC1049LP5E amplifier I/Os are internally matched to 50 Ω. and the device is supplied in a compact, leadless 5 mm × 5 mm LFCSP package.

HMC1049LP5E

Figure 1.



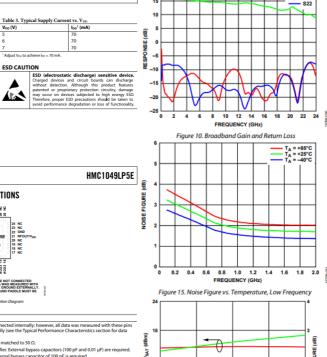
Vpp (V)

ESD CAUTION

180

Pin No.	Mnemonic	Description ¹	
1, 3, 6 to 12, 14, 17 to 20, 23 to 29, 31, 32	NC	No Connect. These pins are not connected internally; however, all data was measured with these pins connected to RF/dc ground externally (see the Typical Performance Characteristics section for data plots).	۲ ۲
5	RFIN	RF Input. This pin is dc-coupled and matched to 50 Ω.	명
2	Voo	Power Supply Voltage for the Amplifier. External bypass capacitors (100 pF and 0.01 µF) are required.	E.
30	ACG1	Low Frequency Termination. An external bypass capacitor of 100 pF is required.	a 12
21	RFOUT/V _{DD}	RF Output/Alternate Power Supply Voltage for the Amplifier. An external bias tee is required when used as alternative V ₂₀ . This pin is dc-coupled and matched to 50 Ω .	ĝ ¹
15, 16	ACG2, ACG3	Low Frequency Termination. External bypass capacitors of 100 pF are required.	MIN
13	Vas	Gate Control for Amplifier. Adjust the voltage to achieve Ipp = 70 mA. External bypass capacitors of 100 pF, 0.01 µF, and 4.7µF are required.	
4, 22	GND	Ground. Connect Pin 4 and Pin 22 to RF/dc ground.	
0	EP	Exposed Pad. The exposed ground paddle must be connected to RF/dc ground.	

¹ See the Interface Schematics section for pin interface



6.0 Vpp (V) Figure 27. Gain, PSAT, and Noise Figure vs. VDD at 12 GHz

5.0

5.5

GAIN

NOISE FIGURE

7.0

P BAT

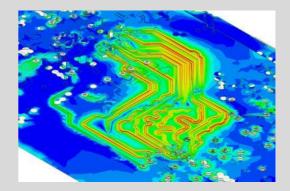
6.5



- Schematic Level
- Layout Level



- Structural model SPICE
- Behavioral model IBIS
- Scattering model S-parameter

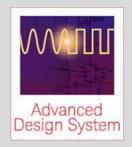




• ADS by Keysight

- Electronics Desktop by Ansys
- LTspice by Analog Devices

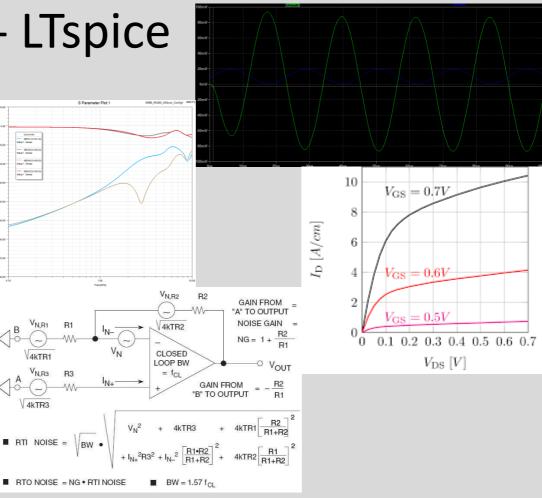
• Qucs (under GPL license)

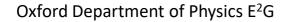






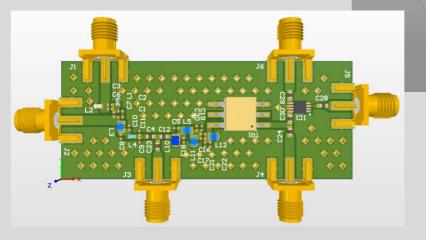
- Transient
- AC
- DC Sweep
- Noise





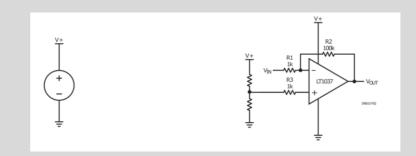


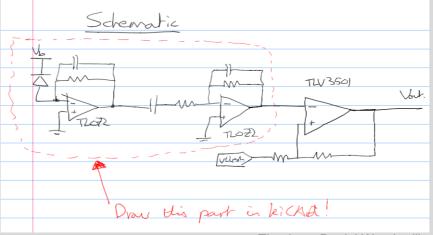
• Layout Level - Slwave





- Transient
- AC
- Noise





Thanks to Daniel Weatherill